

# **Description**

The AOD603-HXY uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

# PIT MOSE ST G1

TO252-4L

#### **General Features**

 $V_{DS} = 60V I_{D} = 20A$ 

 $R_{DS(ON)}$  < 34m $\Omega$  @  $V_{GS}$ =10V

 $V_{DS} = -60V I_{D} = -15A$ 

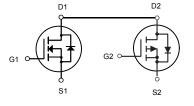
 $R_{DS(ON)}$  < 86 m $\Omega$  @  $V_{GS}$ =-10V

## **Application**

Wireless charging

Boost driver

Brushless motor



N-Channel MOSFET

P-Channel MOSFE

# **Package Marking and Ordering Information**

	<u> </u>		
Product ID	Pack	Marking	Qty(PCS)
AOD603-HXY	TO252-4L	6020 XXXX	2500

## Absolute Maximum Ratings (T<sub>C</sub>=25<sup>°</sup>Cunless otherwise noted)

	P	Rati			
Symbol	Parameter	N-Channel	P-Channel	Units	
VDS	Drain-Source Voltage	60	-60	V	
VGS	Gate-Source Voltage	±20	±20	V	
I <sub>D</sub> @T <sub>A</sub> =25℃	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	20	-15	Α	
I <sub>D</sub> @T <sub>A</sub> =70 ℃	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	14	-8.5	Α	
IDM	Pulsed Drain Current <sup>2</sup>	60	-30	Α	
EAS	Single Pulse Avalanche Energy <sup>3</sup>	22	29.8	mJ	
IAS	Avalanche Current	21	-24.4	Α	
P <sub>D</sub> @T <sub>A</sub> =25°C	Total Power Dissipation <sup>4</sup>	50	50	W	
TSTG	Storage Temperature Range	-55 to 150	-55 to 150	$^{\circ}$	
TJ	Operating Junction Temperature Range	-55 to 150	-55 to 150	°C	
R₀JA	Thermal Resistance Junction-Ambient <sup>1</sup>	6.	2	°C/W	
R₀JC	Thermal Resistance Junction-Case <sup>1</sup>	3	3	°C/W	



# N-Channel Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
$BV_{DSS}$	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =250uA	60			V
D	Static Drain Source On Begintance?	V <sub>GS</sub> =10V , I <sub>D</sub> =15A		26	34	0
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =4.5V , I <sub>D</sub> =7A		35	45	mΩ
$V_{GS(th)}$	Gate Threshold Voltage	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250uA	1.0		2.5	V
1	Drain Source Leekens Current	V <sub>DS</sub> =48V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			1	
I <sub>DSS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> =48V , V <sub>GS</sub> =0V , T <sub>J</sub> =55°C			5	uA
Igss	Gate-Source Leakage Current	V <sub>GS</sub> =±20V , V <sub>DS</sub> =0V			±100	nA
gfs	Forward Transconductance	V <sub>DS</sub> =5V , I <sub>D</sub> =15A		25.3		S
$Q_g$	Total Gate Charge (10V)			19		
$Q_{gs}$	Gate-Source Charge	V <sub>DS</sub> =48V , V <sub>GS</sub> =10V , I <sub>D</sub> =15A		2.5		nC
$Q_{gd}$	Gate-Drain Charge			5		
T <sub>d(on)</sub>	Turn-On Delay Time			2.8		
Tr	Rise Time	$V_{DD}$ =30V , $V_{GS}$ =10V , $R_{G}$ =3.3 $\Omega$		16.6		
T <sub>d(off)</sub>	Turn-Off Delay Time	I <sub>D</sub> =15A		21.2		ns
Tf	Fall Time			5.6		
Ciss	Input Capacitance			1027		
Coss	Output Capacitance	V <sub>DS</sub> =15V , V <sub>GS</sub> =0V , f=1MHz		65		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			46		

## **Diode Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Is	Continuous Source Current <sup>1,6</sup>	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			20	Α
$V_{SD}$	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V , I <sub>S</sub> =1A , T <sub>J</sub> =25°C			1.2	V

#### Note

<sup>1.</sup> The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.

<sup>2.</sup>The data tested by pulsed , pulse width  $\leq$  300us , duty cycle  $\leq$  2%

<sup>3.</sup> The EAS data shows Max. rating . The test condition is  $V_{DD}$ =25V,  $V_{GS}$ =10V, L=0.1mH,  $I_{AS}$ =21A

<sup>4.</sup> The power dissipation is limited by 150°C junction temperature

<sup>5.</sup> The data is theoretically the same as  $I_D$  and  $I_{DM}$ , in real applications, should be limited by total power dissipation.



## P-Channel Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
$BV_{DSS}$	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =-250uA	-60			V
D	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =-10V , I <sub>D</sub> =-10A		78	86	0
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance-	V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-5A		85	100	1115.2
$V_{GS(th)}$	Gate Threshold Voltage	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =-250uA	-1.0		-2.5	V
1	Drain Source Leakage Current	V <sub>DS</sub> =-48V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			1	
I <sub>DSS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> =-48V , V <sub>GS</sub> =0V , T <sub>J</sub> =55°C			5	V S mΩ S V UA DO nA S C C nC C ns C pF
Igss	Gate-Source Leakage Current	V <sub>GS</sub> =±20V , V <sub>DS</sub> =0V			±100	nA
gfs	Forward Transconductance	V <sub>DS</sub> =-5V , I <sub>D</sub> =-4A		8.7		S
$Q_g$	Total Gate Charge (-4.5V)			11.8		
$Q_{gs}$	Gate-Source Charge	V <sub>DS</sub> =-12V , V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-6A		1.9		nC
$Q_{gd}$	Gate-Drain Charge			6.5		
T <sub>d(on)</sub>	Turn-On Delay Time			8.8		
Tr	Rise Time	$V_{DD}$ =-15 $V$ , $V_{GS}$ =-10 $V$ , $R_{G}$ =3.3 $\Omega$ ,		19.6		
T <sub>d(off)</sub>	Turn-Off Delay Time	I <sub>D</sub> =-1A		47.2		ns
Tf	Fall Time			9.6		
Ciss	Input Capacitance			1080		
Coss	Output Capacitance	V <sub>DS</sub> =-15V , V <sub>GS</sub> =0V , f=1MHz		73		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			50		

### **Diode Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Is	Continuous Source Current <sup>1,5</sup>	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			-15	Α
V <sub>SD</sub>	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V , I <sub>S</sub> =-1A , T <sub>J</sub> =25°C			-1	V

#### Note:

<sup>1.</sup>The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.

<sup>2.</sup>The data tested by pulsed , pulse width  $\,\leq\,300\text{us}$  , duty cycle  $\,\leq\,2\%$ 

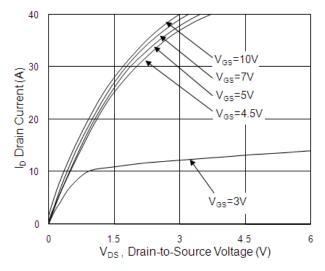
<sup>3.</sup> The EAS data shows Max. rating . The test condition is  $V_{DD}$ =-25V,  $V_{GS}$ =-10V, L=0.1mH,  $I_{AS}$ =-24.4A

<sup>4.</sup> The power dissipation is limited by 150°C junction temperature

<sup>5.</sup> The data is theoretically the same as  $I_D$  and  $I_{DM}$ , in real applications, should be limited by total power dissipation.



# **N-Channel Typical Characteristics**



**Fig.1 Typical Output Characteristics** 

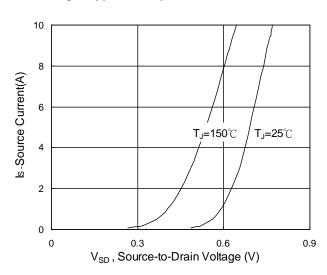


Fig.3 Source Drain Forward Characteristics

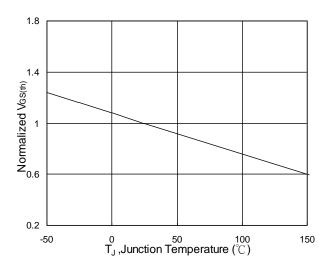


Fig.5 Normalized V<sub>GS(th)</sub> vs. T<sub>J</sub>

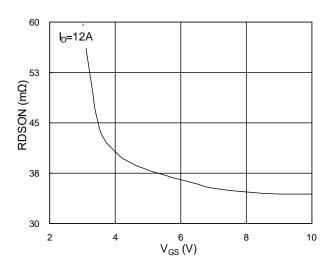


Fig.2 On-Resistance vs. G-S Voltage

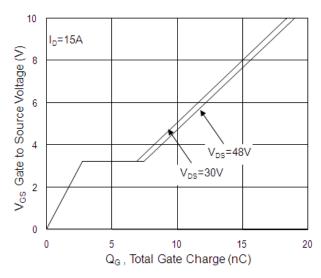


Fig.4 Gate-Charge Characteristics

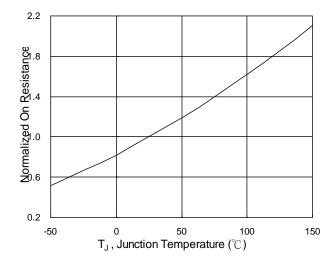
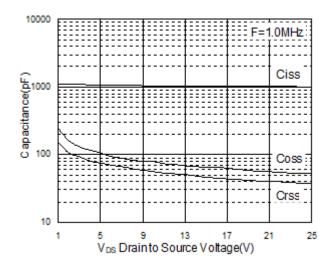


Fig.6 Normalized R<sub>DSON</sub> vs. T<sub>J</sub>



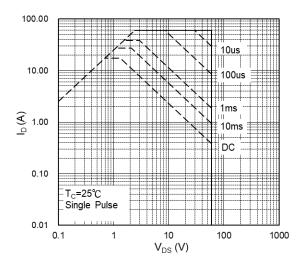


Fig.7 Capacitance

Fig.8 Safe Operating Area

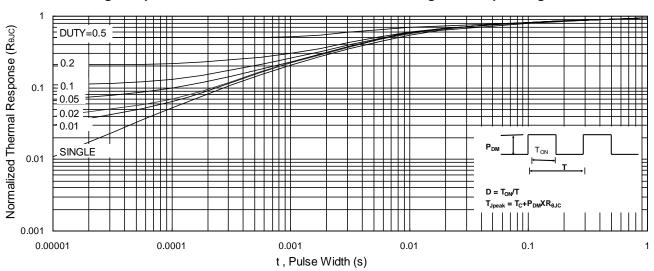


Fig.9 Normalized Maximum Transient Thermal Impedance

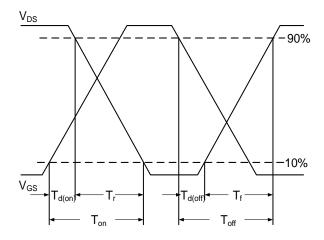


Fig.10 Switching Time Waveform

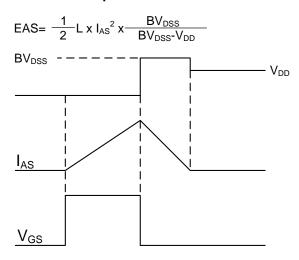


Fig.11 Unclamped Inductive Switching Waveform



# **P-Channel Typical Characteristics**

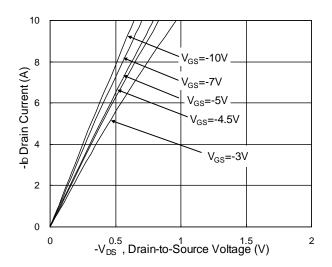


Fig.1 Typical Output Characteristics

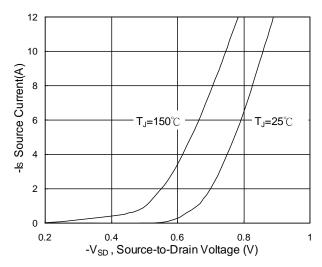


Fig.3 Source Drain Forward Characteristics

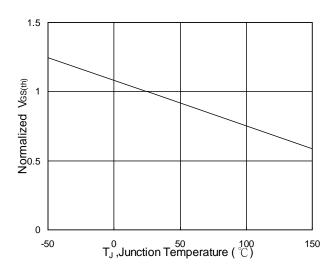


Fig.5 Normalized  $V_{\text{GS(th)}}$  vs.  $T_{\text{J}}$ 

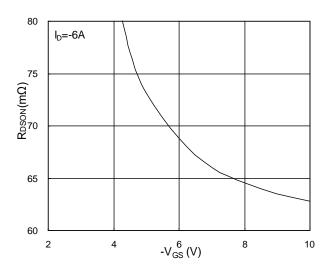


Fig.2 On-Resistance vs. G-S Voltage

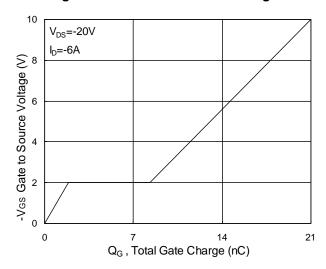


Fig.4 Gate-Charge Characteristics

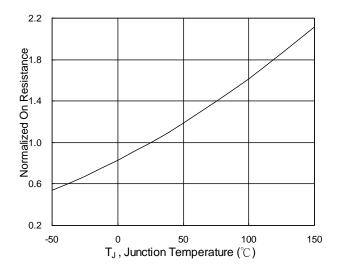
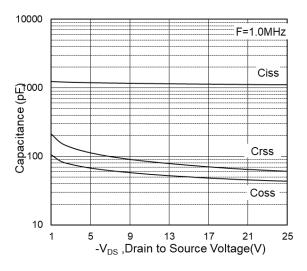


Fig.6 Normalized R<sub>DSON</sub> vs. T<sub>J</sub>





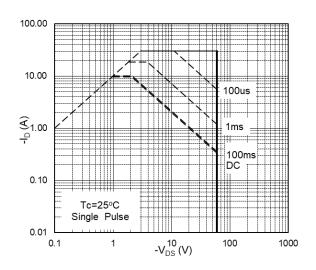


Fig.7 Capacitance

Fig.8 Safe Operating Area

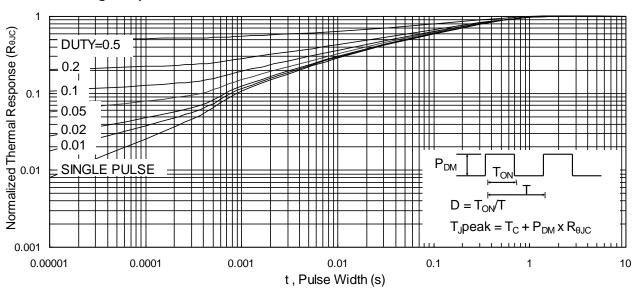


Fig.9 Normalized Maximum Transient Thermal Impedance

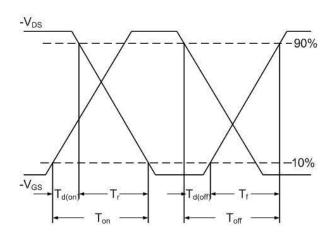


Fig.10 Switching Time Waveform

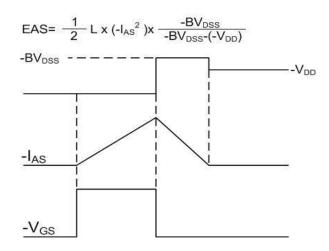
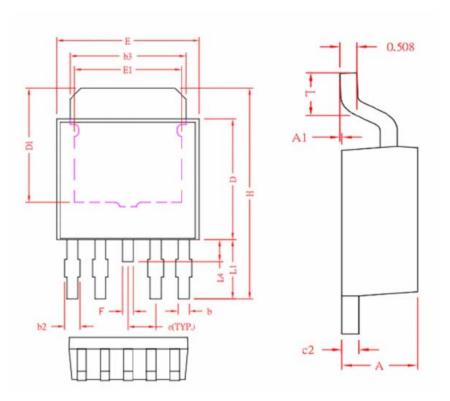


Fig.11 Unclamped Inductive Switching Waveform



# **TO252-4L Package Information**



C	OMMON D	IMENSION	NS
(UNITS	OF MEAS	URE=MILI	IMETER
SYMBOL	MIN	NOM	MAX
A	2.20	2.30	2.40
A1	0	0.08	0.15
ь	0.45	0.53	0.60
b2	0.50	0.65	0.80
ь3	5.20	5. 35	5.50
c2	0.45	0.50	0.55
D	5.40	5. 60	5.80
D1	4.57	-	-
E	6.40	6.60	6.80
E1	3.81	-	-
е	1	. 27 REF.	
F	0.40	0.50	0.60
Н	9.40	9.80	10.20
L	1.40	1.59	1.77
L1	2.40	2.70	3.00
L4	0.80	1.00	1.20

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